

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

# 2SC2290A

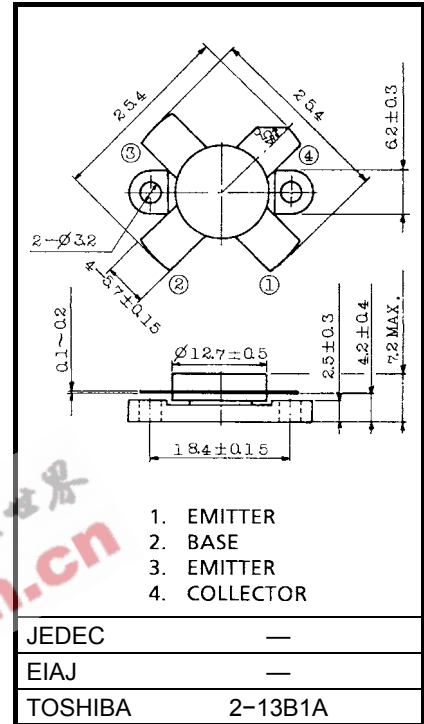
2~30MHz SSB LINEAR POWER AMPLIFIER APPLICATIONS  
(LOW SUPPLY VOLTAGE USE)

Unit in mm

- Specified 12.5V, 28MHz Characteristics
- Output Power :  $P_o = 60W_{PEP}$  (Min.)
- Power Gain :  $G_p = 11.8dB$  (Min.)
- Collector Efficiency :  $\eta_C = 35%$  (Min.)
- Intermodulation Distortion:  $IMD = -30dB$  (Max.)

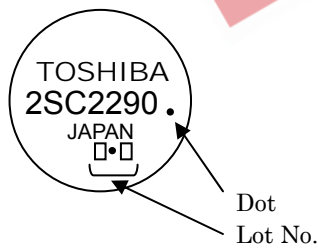
### MAXIMUM RATINGS ( $T_c = 25^\circ C$ )

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	$V_{CBO}$	45	V
Collector-Emitter Voltage	$V_{CES}$	45	V
Collector-Emitter Voltage	$V_{CEO}$	18	V
Emitter-Base Voltage	$V_{EBO}$	4	V
Collector Current	$I_C$	20	A
Collector Power Dissipation	$P_C$	175	W
Junction Temperature	$T_j$	175	$^\circ C$
Storage Temperature Range	$T_{stg}$	-65~175	$^\circ C$



Weight: 5.2g

### MARKING



## ELECTRICAL CHARACTERISTICS (T<sub>c</sub> = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector-Emitter Breakdown Voltage	V <sub>(BR)</sub> CEO	I <sub>C</sub> = 100mA, I <sub>B</sub> = 0	18	—	—	V
Collector-Emitter Breakdown Voltage	V <sub>(BR)</sub> CES	I <sub>C</sub> = 100mA, V <sub>EB</sub> = 0	45	—	—	V
Emitter-Base Breakdown Voltage	V <sub>(BR)</sub> EBO	I <sub>E</sub> = 1mA, I <sub>C</sub> = 0	4	—	—	V
DC Current Gain	h <sub>FE</sub>	V <sub>CE</sub> = 5V, I <sub>C</sub> = 10A *	10	—	150	—
Collector Output Capacitance	C <sub>ob</sub>	V <sub>CB</sub> = 12.5V, I <sub>E</sub> = 0 f = 1MHz	—	—	500	pF
Power Gain	G <sub>p</sub>	V <sub>CC</sub> = 12.5V, f <sub>1</sub> = 28.000MHz, f <sub>2</sub> = 28.001MHz I <sub>idle</sub> = 50mA P <sub>o</sub> = 60W <sub>PEP</sub> (Fig.)	11.8	13.8	—	dB
Input Power	P <sub>i</sub>		—	2.5	4	W <sub>PEP</sub>
Collector Efficiency	η <sub>C</sub>		35	—	—	%
Intermodulation Distortion	IMD		—	—	-30	dB
Series Equivalent Input Impedance	Z <sub>in</sub>		—	1.02 -j0.17	—	Ω
Series Equivalent Output Impedance	Z <sub>out</sub>	—	0.86 -j0.21	—	Ω	

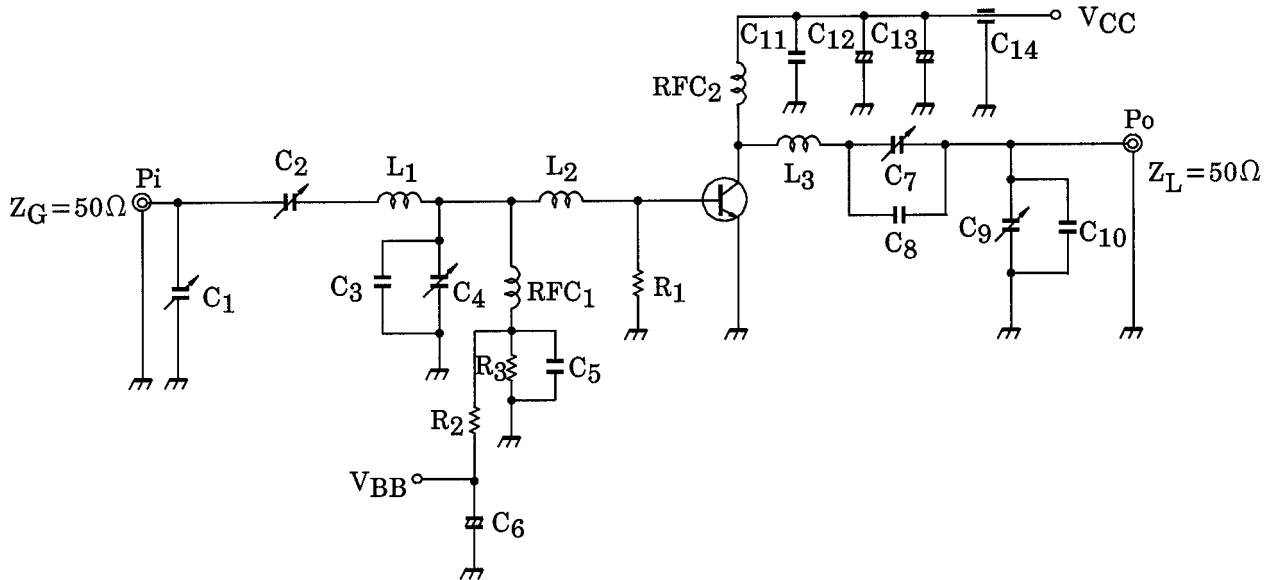
\* Pulse Test: Pulse Width ≤ 100μs, Duty Cycle ≤ 3%

## RESTRICTIONS ON PRODUCT USE

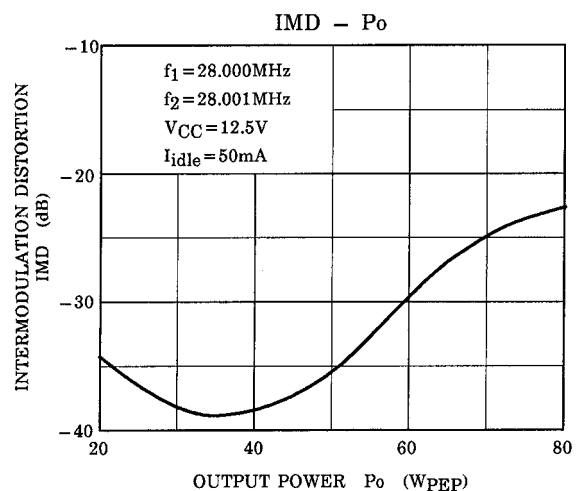
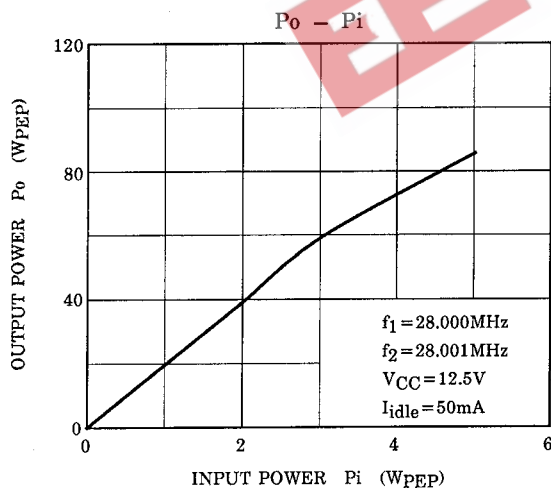
030619EAA

- The information contained herein is subject to change without notice.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of TOSHIBA or others.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.  
In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- TOSHIBA products should not be embedded to the downstream products which are prohibited to be produced and sold, under any law and regulations.

Fig. Pi TEST CIRCUIT



- |   |  |
|---|--|
| C <sub>1</sub> , C <sub>2</sub> , C <sub>4</sub> , C <sub>7</sub> : 7~150pF | L <sub>1</sub> : φ0.8 ENAMEL COATED COPPER WIRE, 9ID, 6T     |
| C <sub>3</sub> : 250pF  | L <sub>2</sub> : φ1 SILVER PLATED COPPER WIRE, 9ID, 2T       |
| C <sub>5</sub> : 0.4μF  | L <sub>3</sub> : φ1.5 ENAMEL COATED COPPER WIRE, 9ID, 5T     |
| C <sub>6</sub> : 100μF 10WV   | RFC <sub>1</sub> : φ0.8 ENAMEL COATED COPPER WIRE, 9ID, 20T  |
| C <sub>8</sub> : 150pF  | RFC <sub>2</sub> : φ1.5 ENAMEL COATED COPPER WIRE, 12ID, 15T |
| C <sub>9</sub> : 10~200pF   | R <sub>1</sub> : 5.6Ω (1/2W)                                 |
| C <sub>10</sub> : 600pF   | R <sub>2</sub> : 5Ω (5W)                                     |
| C <sub>11</sub> : 0.4μF   | R <sub>3</sub> : 1.5Ω (10W)                                  |
| C <sub>12</sub> , C <sub>13</sub> : 22μF 35WV                               |  |
| C <sub>14</sub> : 1000pF  |  |
- (FEED THROUGH)



## CAUTION

These are only typical curves and devices are not necessarily guaranteed at these curves.